

EXTENDING SYNCHROTRON X-RAY MICROSCOPY TO THE LABORATORY - CORRELATIVE IMAGING TECHNIQUE FOR INDUSTRIAL AND ENVIRONMENTAL APPLICATION

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Abstract

As X-Ray Microscopy is extended from the Synchrotron community to the laboratory, correlation to other imaging techniques is vital for many reasons. Partly due to the need to show where the technique fits in the landscape of multi length scale imaging and partly to show the efficacy of the application by correlating similar imaging modalities. We will show through various applications from the fields of Materials, Life Science, Geo Science, and Electronics how X-Ray microscopy complements existing technology, not replacing any technique, but adding further information to gain a deeper understanding of the scientific application. The technical possibility to perform in-situ and XRD (X-Ray Diffraction) experiments makes the X-Ray Microscope to a versatile high resolution 3D imaging device.

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